TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74LVX273F,TC74LVX273FT

#### Octal D-Type Flip-Flop with Clear

The TC74LVX273F/ FT is a high-speed CMOS octal D-flip flop fabricated with silicon gate CMOS technology. Designed for use in 3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

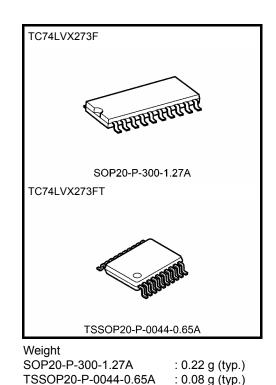
This device is suitable for low-voltage and battery operated systems.

Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse. When the  $\overline{\text{CLR}}$  input is held low, the Q outputs are in the low logic level independent of the other inputs.

An input protection circuit ensures that 0 to 5.5V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5V to 3V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

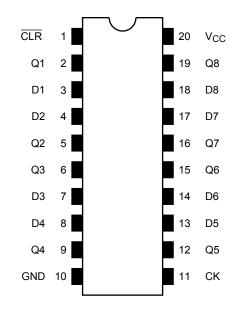
#### Features

- High-speed:  $f_{max} = 150 \text{ MHz}$  (typ.) (V<sub>CC</sub> = 3 V)
- Low power dissipation:  $I_{CC} = 4 \ \mu A \ (max) \ (Ta = 25^{\circ}C)$
- Input voltage level:  $V_{IL} = 0.8 V (max) (V_{CC} = 3 V)$ 
  - $V_{IH} = 2.0 V (min) (V_{CC} = 3 V)$
- Power-down protection provided on all inputs
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Low niose:  $V_{OLP} = 0.8 V (max)$
- Pin and function compatible with 74HC273

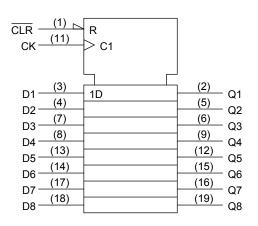


# <u>TOSHIBA</u>

## Pin Assignment (top view)



## **IEC Logic Symbol**

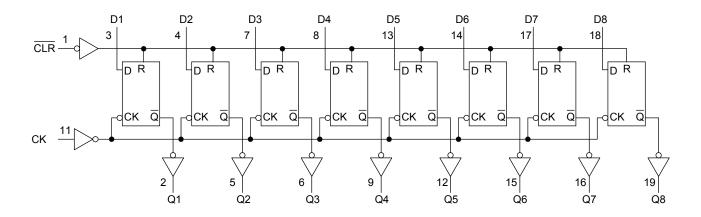


### **Truth Table**

	Inputs	Outputs	Function		
	D	СК	Q	runction	
L	Х	Х	L	Clear	
Н	L		L	_	
Н	н		Н	_	
Н	Х	$\neg$	Qn	No change	

X: Don't care

## System Diagram



#### Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5 to 7.0	V
DC input voltage	V <sub>IN</sub>	-0.5 to 7.0	V
DC output voltage	V <sub>OUT</sub>	$-0.5$ to $V_{CC}$ + 0.5	V
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	IOK	±20	mA
DC output current	IOUT	±25	mA
DC V <sub>CC</sub> /ground current	ICC	±75	mA
Power dissipation	PD	180	mW
Storage temperature	T <sub>stg</sub>	-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2.0 to 3.6	V
Input voltage	V <sub>IN</sub>	0 to 5.5	V
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40 to 85	°C
Input rise and fall time	dt/dv	0 to 100	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics		Sym- bol			Ta = 25°C		Ta = −40 to 85°C		Unit		
					$V_{CC}(V)$	Min	Тур.	Max	Min	Max	
					2.0	1.5	_	_	1.5	_	
	H-level	VIH	—		3.0	2.0	_	_	2.0	_	
Input voltage					3.6	2.4	_	_	2.4	_	v
input voltage					2.0	_	_	0.5	_	0.5	v
	L-level	V <sub>IL</sub>	—		3.0	_	_	0.8	_	0.8	
					3.6	_	_	0.8	_	0.8	
	H-level \	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	_	1.9	_	
				I <sub>OH</sub> = -50 μA	3.0	2.9	3.0	_	2.9	_	
Output voltage				I <sub>OH</sub> = -4 mA	3.0	2.58	_	_	2.48	_	v
Output voltage			$V_{OL}$ $V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OL</sub> = 50 μA	2.0	_	0	0.1	_	0.1	v
	L-level	V <sub>OL</sub>		I <sub>OL</sub> = 50 μA	3.0	_	0	0.1	_	0.1	
				I <sub>OL</sub> = 4 mA	3.0	_	_	0.36	_	0.44	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		3.6	_		±0.1	_	±1.0	μA
Quiescent supply cu	irrent	ICC	$V_{IN} = V_{CC}$ or GND		3.6			4.0		40.0	μA

## Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	nbol Test Condition		Ta = 25°C	Ta =	Unit	
			V <sub>CC</sub> (V)	Limit	Limit		
Minimum pulse width	t <sub>W (L)</sub>		2.7	8.0	9.5	ns	
(CK)	t <sub>W (H)</sub>		$\textbf{3.3}\pm\textbf{0.3}$	5.5	6.5	115	
Minimum pulse width	<b>4</b>		2.7	7.5	8.5	20	
( CLR )	t <sub>W (L)</sub>	—	$\textbf{3.3}\pm\textbf{0.3}$	5.0	6.0	ns	
Minimum set-up time	t <sub>s</sub>		2.7	8.0	9.5	- ns	
		—	$\textbf{3.3}\pm\textbf{0.3}$	5.5	6.5		
Minimum hold time	•		2.7	1.0	1.0	20	
Minimum hold time	t <sub>h</sub>		$\textbf{3.3}\pm\textbf{0.3}$	1.0	1.0	ns	
Minimum removal time	+		2.7	4.0	4.0	20	
(CLR)	t <sub>rem</sub>		$\textbf{3.3}\pm\textbf{0.3}$	2.5	2.5	ns	

### AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol Test Condition				Ta = 25°C		Ta = -40 to 85°C		Unit	
			V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	
	t		2.7	15	_	9.0	16.9	1.0	20.5	
Propagation delay time	t <sub>pLH</sub>		2.1	50		11.5	20.4	1.0	24.0	ns
(CK-Q)	t		$3.3\pm0.3$	15		7.1	11.0	1.0	13.0	115
	t <sub>pHL</sub>		5.5 ± 0.5	50		9.6	14.5	1.0	16.5	
	t <sub>pHL</sub>	_	2.7	15		9.3	17.6	1.0	20.5	- ns
Propagation delay time				50		11.8	21.1	1.0	24.0	
(CLR -Q)			$3.3\pm0.3$	15		7.3	11.5	1.0	13.5	
				50		9.8	15.0	1.0	17.0	
	f <sub>max</sub>		2.7	15	55	110		45		MHz
Maximum clock frequency				50	45	60		40		
			3.3 ± 0.3	15	95	150	_	80	_	
			$5.5 \pm 0.5$	50	60	90	_	50	_	
Output to output skew	t <sub>osLH</sub>	(Note 1)	2.7	50			1.5		1.5	ns
	t <sub>osHL</sub>		$\textbf{3.3}\pm\textbf{0.3}$	50	_		1.5		1.5	115
Input capacitance	C <sub>IN</sub>			(Note 2)	_	4	10		10	pF
Power dissipation capacitance	C <sub>PD</sub>			(Note 3)		31				pF

Note 1: Parameter guaranteed by design.  $(t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|)$ 

Note 2: Parameter guaranteed by design.

Note 3: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

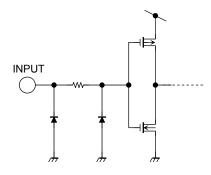
 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per F/F)}$ 

And the total C<sub>PD</sub> when n pcs. of F/F operate can be gained by the following equation: C<sub>PD</sub> (total) = 22 + 9  $\cdot$  n

# Noise Characteristics (Ta = 25°C, input: $t_r = t_f = 3 \text{ ns}, C_L = 50 \text{ pF}$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	_	3.3	0.5	0.8	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	_	3.3	-0.5	-0.8	V
Minimum high level dynamic input voltage $V_{IH}$	VIHD		3.3	_	2.0	V
Maximum low level dynamic input voltage $V_{IL}$	V <sub>ILD</sub>		3.3	_	0.8	V

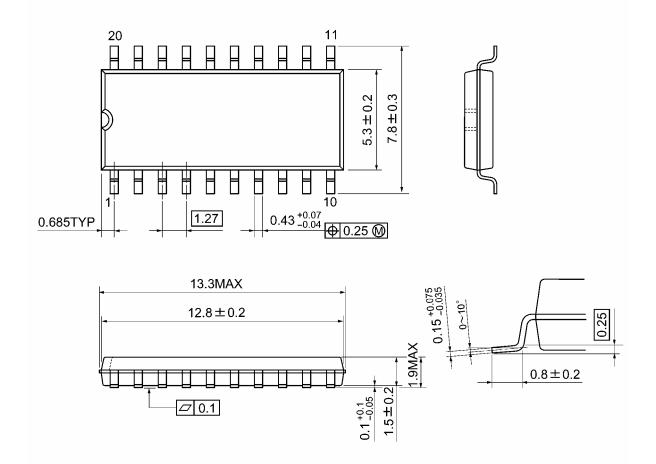
# Input Equivalent Circuit



### **Package Dimensions**

SOP20-P-300-1.27A

Unit: mm

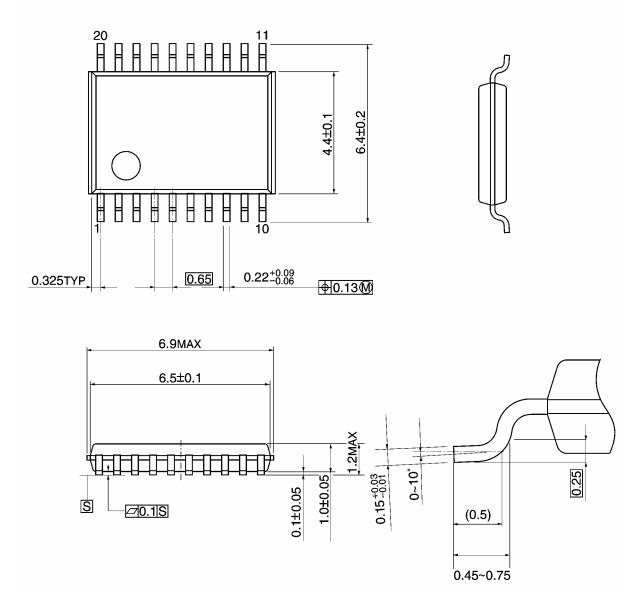


Weight: 0.22 g (typ.)

## Package Dimensions

TSSOP20-P-0044-0.65A

Unit: mm



Weight: 0.08 g (typ.)

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20070701-EN GENERAL

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